Sample Results Summary Sheet Please return this form to the Curator for each allocated Sample

Sample ID: RA-QD02-0050

PI: Tomoki Nakamura

Type and date of analysis performed:

XRD Jan/28/2011~ Feb/3/2011

SEM Feb/7/2011

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

XRD : OI, HPx, PI SEM : OI, HPx, PI, Tr

Contaminant phases identified: (Al, SUS, carbon particles, etc.)

N/A

Sample handling:

XRD

Attached to carbon fiber with resin.

SEM

Exposed in atmosphere.

Polished by M cross

C-coated (20 nm)

State of sample pre-analysis:

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded (SEM)

State of sample post-analysis:

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded, C-coated (SEM)

N₂ hold in sample holder.

Analysis data Notes: (summary of the attached analysis data and/or images) See attached sheets.

RA-QD02-0050

Analysis S-XRD Microtome SEM (Ibaraki)
Present status Putted butt with a large hole by FIB sampling

SEM/BSE





